

FTM3725

NPN Transistor

- This device is designed for high current, low impedance line driver applications.
- Sourced from process 26.



Absolute Maximum Ratings* T_a=25°C unless otherwise noted

Symbol	Parameter	Value	Units	
V _{CEO}	Collector-Emitter Voltage	40	V	
V _{CBO}	Collector-Base Voltage	60	V	
V _{EBO}	Emitter-Base Voltage	6.0	V	
I _C	Collector Current - Continuous	1.2	Α	
T _J , T _{STG}	Operating and Storage Junction Temperature Range	- 55 ~ 150	°C	

^{*} These ratings are limiting values above whitch the serviceability of any semiconductor device may be impaird.

- These ratings are based on a maximum junction temperature of 150 degrees C.
 These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Electrical Characteristics T_a=25°C unless otherwise noted

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charac	teristics	-	1			
V _{(BR)CEO}	Collector-Emitter Breakdown Voltage *	I _C = 10mA, I _B = 0	40			V
V _{(BR)CES}	Collector-Emitter Breakdown Voltage	$I_C = 10\mu A, V_{BE} = 0$	60			V
V _{(BR)CBO}	Collector-Base Breakdown Voltage	$I_C = 10\mu A, I_E = 0$	60			V
V _{(BR)EBO}	Emitter-Base Breakdown Voltage	$I_E = 10\mu A, I_C = 0$	6.0			V
I _{СВО}	Collector Cutoff Current	$V_{CB} = 50V, I_E = 0$ $V_{CB} = 50V, I_E = 0, T_a = 100^{\circ}C$			100 10	nA μA
On Charac	teristics *			•		
h _{FE}	DC Current Gain	$\begin{split} &I_C = 10\text{mA}, V_{CE} = 1.0\text{V} \\ &I_C = 100\text{mA}, V_{CE} = 1.0\text{V} \\ &I_C = 100\text{mA}, V_{CE} = 1.0\text{V}, T_a = 55^\circ\text{C} \\ &I_C = 300\text{mA}, V_{CE} = 1.0\text{V} \\ &I_C = 500\text{mA}, V_{CE} = 1.0\text{V} \\ &I_C = 500\text{mA}, V_{CE} = 1.0\text{V}, T_a = 55^\circ\text{C} \\ &I_C = 800\text{mA}, V_{CE} = 2.0\text{V} \\ &I_C = 1.0\text{mA}, V_{CE} = 5.0\text{V} \end{split}$	30 60 30 40 35 20 20 25		180	
V _{CE} (sat)	Collector-Emitter Saturation Voltage	$\begin{split} & I_{C} = 10\text{mA}, \ I_{B} = 1.0\text{mA} \\ & I_{C} = 100\text{mA}, \ I_{B} = 10\text{mA} \\ & I_{C} = 300\text{mA}, \ I_{B} = 30\text{mA} \\ & I_{C} = 500\text{mA}, \ I_{B} = 50\text{mA} \\ & I_{C} = 800\text{mA}, \ I_{B} = 80\text{mA} \\ & I_{C} = 1.0\text{mA}, \ I_{B} = 100\text{mA} \end{split}$			0.25 0.26 0.4 0.52 0.8 0.95	V V V V
V _{BE} (sat)	Base-Emitter Saturation Voltage	$\begin{split} &I_C = 10\text{mA},\ I_B = 1.0\text{mA} \\ &I_C = 100\text{mA},\ I_B = 10\text{mA} \\ &I_C = 300\text{mA},\ I_B = 30\text{mA} \\ &I_C = 500\text{mA},\ I_B = 50\text{mA} \\ &I_C = 800\text{mA},\ I_B = 80\text{mA} \\ &I_C = 1.0\text{mA},\ I_B = 100\text{mA} \end{split}$			0.76 0.86 1.1 1.2 1.5 1.7	V V V V

$\textbf{Electrical Characteristics*} \text{ (Continued) } \textbf{T}_{a} = 25^{\circ} \textbf{C unless otherwise noted}$

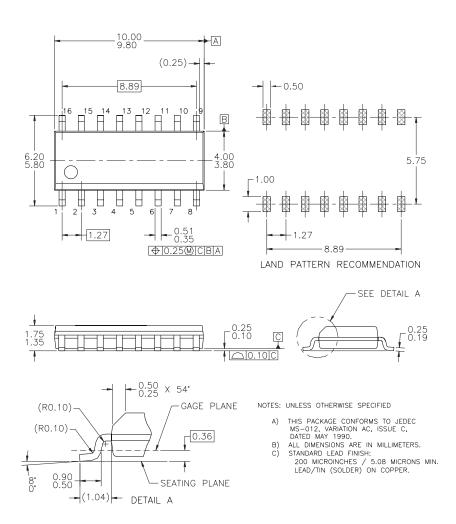
Parameter	Test Condition	Min.	Тур.	Max.	Units	
Small Signal Characteristics						
Current Gain Bandwidth Product	I _C = 50mA, V _{CE} = 10V, f = 100MHz	250			MHz	
Output Capacitance	V _{CB} = 10V, I _E = 0, f = 1.0MHz			15	pF	
Input Capacitance	$V_{EB} = 0.5V, I_{C} = 0, f = 1.0MHz$			65	pF	
Characteristics	·					
Turn-on Time	V _{CC} = 30V, V _{BE} = 3.8V		20		ns	
Delay Time	I _C = 500mA, I _{B1} = 50mA		10		ns	
Rise Time			12		ns	
Turn-off Time	$V_{CC} = 30V, I_C = 500mA$ $I_{B1} = I_{B2} = 50mA$		250		ns	
Storage Time			235		ns	
Fall Time			15		ns	
	al Characteristics Current Gain Bandwidth Product Output Capacitance Input Capacitance Characteristics Turn-on Time Delay Time Rise Time Turn-off Time Storage Time		Current Gain Bandwidth Product $I_C = 50\text{mA}, V_{CE} = 10\text{V}, f = 100\text{MHz}$ 250 Output Capacitance $V_{CB} = 10\text{V}, I_E = 0, f = 1.0\text{MHz}$ Input Capacitance $V_{EB} = 0.5\text{V}, I_C = 0, f = 1.0\text{MHz}$ Characteristics Turn-on Time $V_{CC} = 30\text{V}, V_{BE} = 3.8\text{V}$ Delay Time $I_C = 500\text{mA}, I_{B1} = 50\text{mA}$ Rise Time Turn-off Time $V_{CC} = 30\text{V}, I_C = 500\text{mA}$ Storage Time $I_{B1} = I_{B2} = 50\text{mA}$	Characteristics Current Gain Bandwidth Product I_C = 50mA, V_{CE} = 10V, f = 100MHz 250 Output Capacitance V_{CB} = 10V, I_E = 0, f = 1.0MHz Input Capacitance V_{EB} = 0.5V, I_C = 0, f = 1.0MHz Characteristics Turn-on Time V_{CC} = 30V, V_{BE} = 3.8V 20 Delay Time I_C = 500mA, I_{B1} = 50mA 10 Rise Time V_{CC} = 30V, I_C = 500mA 250 Storage Time I_{B1} = I_{B2} = 50mA 235 Contracteristics I_{B1} = I_{B2} = 50mA 250 Contracteristics I_{B1} = I_{B2} = 50mA 235 Contracteristics I_{B1} = I_{B2} = 50mA 250 Contracteristics I_{B1} = I_{B2} = 50mA 235 Contracteristics I_{C} = 500mA I_{C} = 500mA 235 Contracteristics I_{C} = 500mA 235 Contracteristics I_{C} = 500mA 235 Contracteristics	Current Gain Bandwidth Product I_C = 50mA, V_{CE} = 10V, f = 100MHz 250	

Thermal Characteristics $T_a=25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Max.	Units
P _D	Total Device Dissipation	1.0	W
_	Derate above 25°C	8.0	mW/°C
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient		
	Effectine 4 Die	125	°C/W
	Each Die	240	°C/W

Package Dimensions

SOIC-16



Dimensions in Millimeters

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